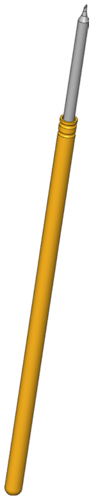
Test Probe INGUN E-Type
E-075 270 026 E 2800
Item E-075-0075

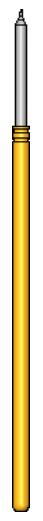
GO TO PRODUCT

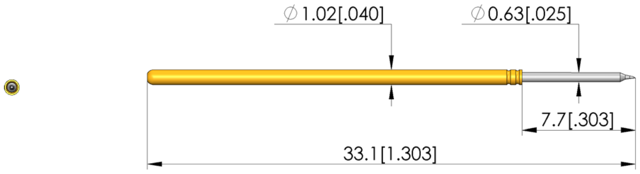
Partner for Future Technology

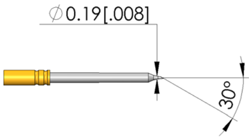
INGUN SELECTION

- Highest contact reliability under challenging test conditions without additional stress on the DUT: up to 25% larger contact surface between test probe and DUT
- When hitting the test surface a spring force up to 100% higher than a standard GKS is available, but the same spring force as a standard GKS is achieved at the working stroke.









General data

Product group:	ICT / FCT (in-circuit test and function test
Sub-product group:	INGUN E-TYPE®
Series:	E-075
Grid:	1.91 mm [75.1 mil]
Contacting from:	Pad
Magnetic:	Yes
Installation type:	Plug-in
Quick-exchange system:	Yes
Adjustable installation height:	No
Non-rotating:	No
Compatible receptacle(s):	KS-075
Min. temperature:	-40 °C [-40 °F]
Max. temperature:	80 °C [176 °F]
RoHS-compliant:	Yes

Tip style data

Tip style:	70 asymmetric slanted needle tip
Tip diameter:	0.2 mm [.007 in]
Tip style surface:	E palladium / nickel
Tip style material:	2 steel

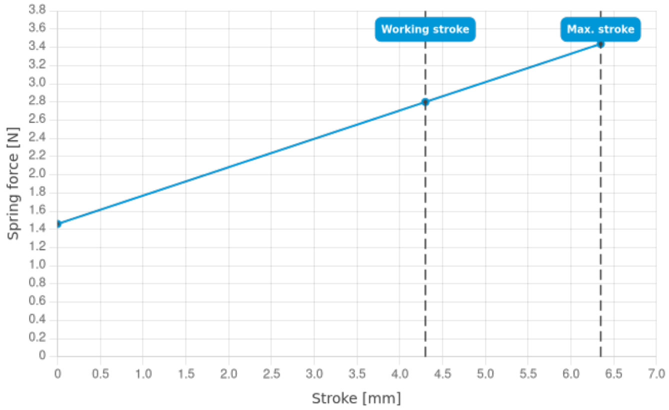
Electrical data

Current load capacity / rated current:	3 A
Typical resistance (Ri):	20 mOhm

Mechanical data

Total length:	33.1 mm [1.3 in]
Barrel diameter:	1.02 mm [.04 in]
Maximum stroke:	6.35 mm [.25 in]
Spring pre-load:	1.46 N [5.25 ozf]
Collar height:	00
Spring force at working stroke:	2.8 N [10 ozf]
Recommended working stroke:	4.3 mm [.169 in]

ICT/FCT TEST PROBES



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